



UTT8P03

Power MOSFET

-8A, -30V P-CHANNEL POWER MOSFET

DESCRIPTION

The UTC **UTT8P03** is a P-channel MOSFET, it uses UTC's advanced technology to provide the customers with a minimum on state resistance, etc.

The UTC **UTT8P03** is suitable for battery switches, load switches and power management, etc.

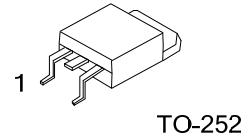
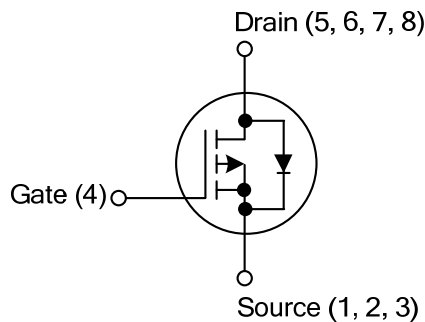
FEATURES

* $R_{DS(ON)} < 33\text{ m}\Omega$ @ $V_{GS} = -10\text{V}$, $I_D = -8.0\text{A}$

$R_{DS(ON)} < 51\text{ m}\Omega$ @ $V_{GS} = -4.5\text{V}$, $I_D = -8.0\text{A}$

* Low $R_{DS(ON)}$

SYMBOL



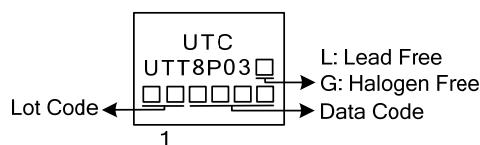
ORDERING INFORMATION

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
UTT8P03L-TN3-R	UTT8P03G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

UTT8P03G-TN3-R	(1)Packing Type (2)Package Type (3)Green Package	(1) R: Tape Reel (2) TN3: TO-252 (3) G: Halogen Free and Lead Free, L: Lead Free
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MARKING



■ ABSOLUTE MAXIMUM RATINGS ($T_C=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	RATINGS	UNIT
Drain-Source Voltage	V_{DSS}	-30	V
Gate-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current	I_D	-8	A
Pulsed Drain Current ($t=300\mu\text{s}$)	I_{DM}	-32	A
Avalanche Energy, Single Pulsed (Note 3)	E_{AS}	22	mJ
Peak Diode Recovery dv/dt (Note 4)	dv/dt	1.85	V/ns
Power Dissipation	P_D	41	W
Junction Temperature	T_J	+150	$^{\circ}\text{C}$
Storage Temperature Range	T_{STG}	-50 ~ +150	$^{\circ}\text{C}$

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. Repetitive Rating: Pulse width limited by maximum junction temperature.

3. $L=0.1\text{mH}$, $I_{AS}=-21\text{A}$, $V_{DD}=-25\text{V}$, $R_G=25\Omega$, Starting $T_J=25^{\circ}\text{C}$

4. $I_{SD} \leq -8\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J=25^{\circ}\text{C}$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	60	$^{\circ}\text{C}/\text{W}$
Junction to Case	θ_{JC}	3.04	$^{\circ}\text{C}/\text{W}$

Note: The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.

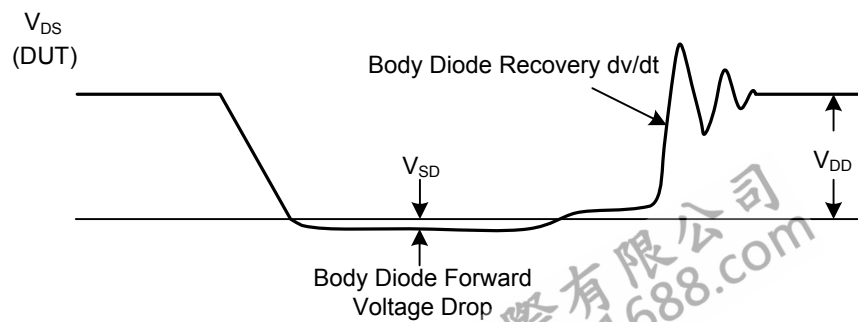
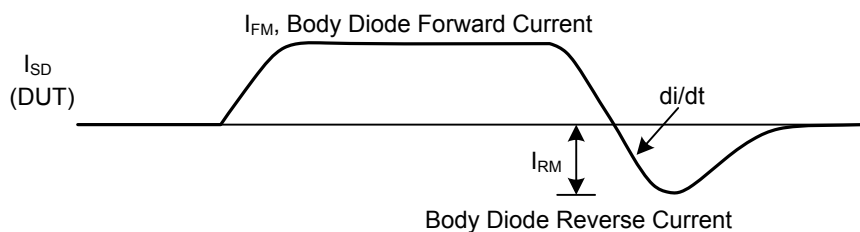
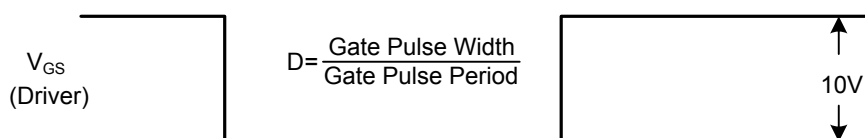
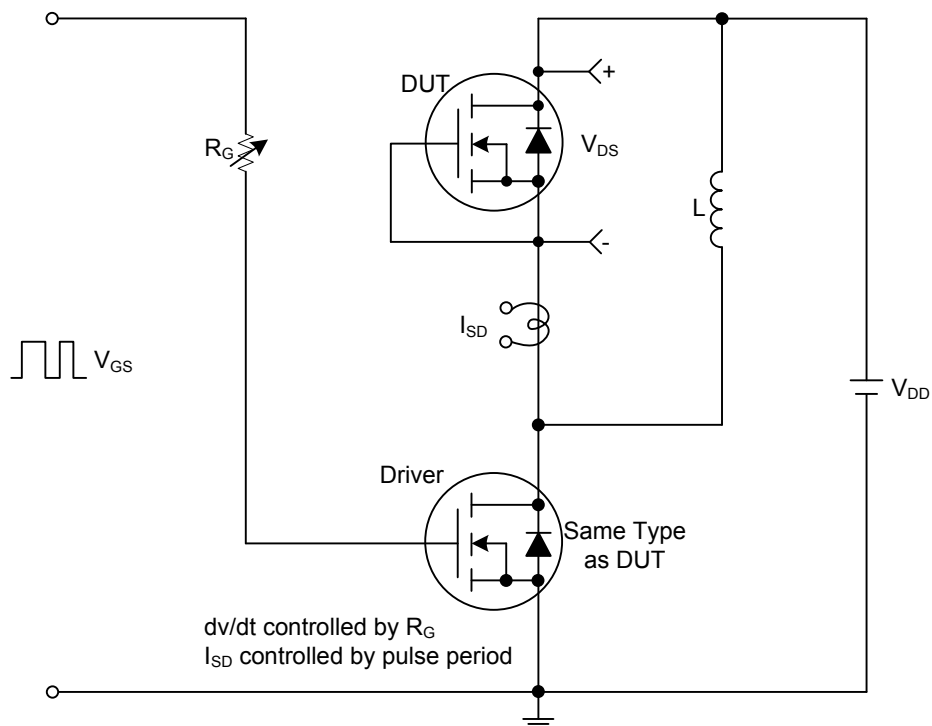
■ ELECTRICAL CHARACTERISTICS ($T_J=25^{\circ}\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC PARAMETERS							
Drain-Source Breakdown Voltage		BV _{DSS}	I _D =-250μA, V _{GS} =0V	-30			V
Zero Gate Voltage Drain Current		I _{DSS}	V _{DS} =-30V, V _{GS} =0V			-1	μA
Gate-Source Leakage Current	Forward	I _{GSS}	V _{GS} =+20V, V _{DS} =0V			+100	nA
	Reverse		V _{GS} =-20V, V _{DS} =0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} =V _{GS} , I _D =-250μA	-1.0		-3.0	V
Static Drain-Source On-State Resistance (Note 1)		R _{DS(ON)}	V _{GS} =-10V, I _D =-8.0A			33	mΩ
			V _{GS} =-4.5V, I _D =-8.0A			51	mΩ
DYNAMIC PARAMETERS							
Input Capacitance		C _{ISS}	V _{GS} =0V, V _{DS} =-10V, f=1.0MHz		1200		pF
Output Capacitance		C _{OSS}			185		pF
Reverse Transfer Capacitance		C _{RSS}			115		pF
SWITCHING PARAMETERS							
Total Gate Charge (Note 1)		Q _G	V _{GS} =-4.5V, V _{DD} =-24V, I _D =-8A I _G =1mA (Note 1, 2)		12.5		nC
Gate to Source Charge		Q _{GS}			3.8		nC
Gate to Drain Charge		Q _{GD}			5.7		nC
Turn-ON Delay Time (Note 1)		t _{D(ON)}	V _{GS} =-4.5V, V _{DD} =-15V, I _D =-8A R _G =25Ω (Note 1, 2)		8		ns
Rise Time		t _R			17		ns
Turn-OFF Delay Time		t _{D(OFF)}			70		ns
Fall-Time		t _F			41		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Continuous Source-Drain Diode Current		I _S				-8	A
Pulse Diode Forward Current		I _{SM}				-32	A
Body Diode Voltage (Note 1)		V _{SD}	I _S =-8A, V _{GS} =0V			-1.5	V
Reverse Recovery Time (Note 1)		t _{rr}	V _{GS} =0V, I _S =-8A, dI _F /dt=-100A/μs		170		nC
Reverse Recovery Charge		Q _{rr}			250		nS

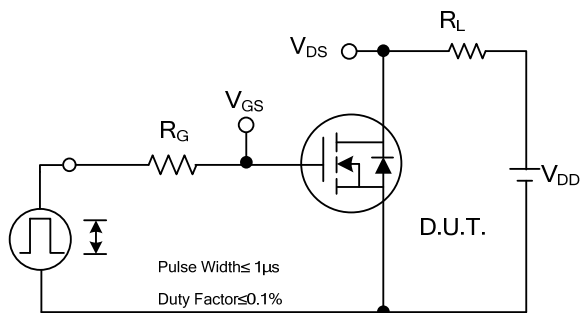
Notes: 1. Pulse test; pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

2. Essentially independent of operating temperature.

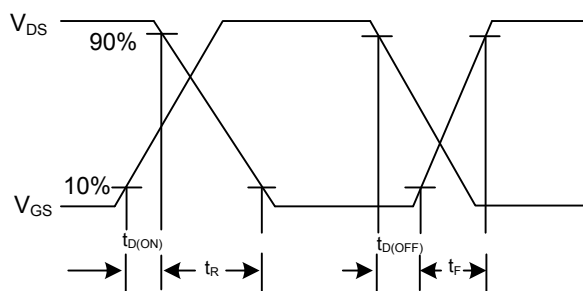
■ TEST CIRCUITS AND WAVEFORMS



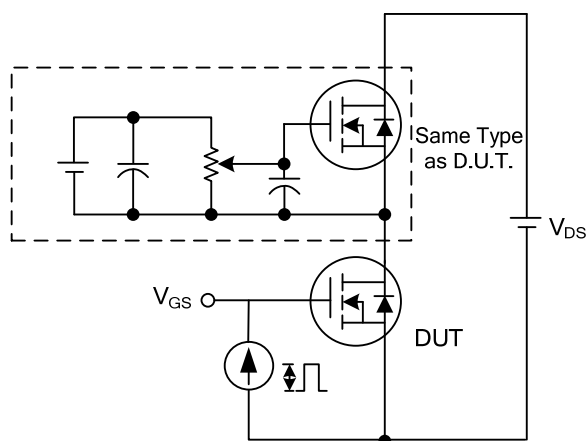
TEST CIRCUITS AND WAVEFORMS



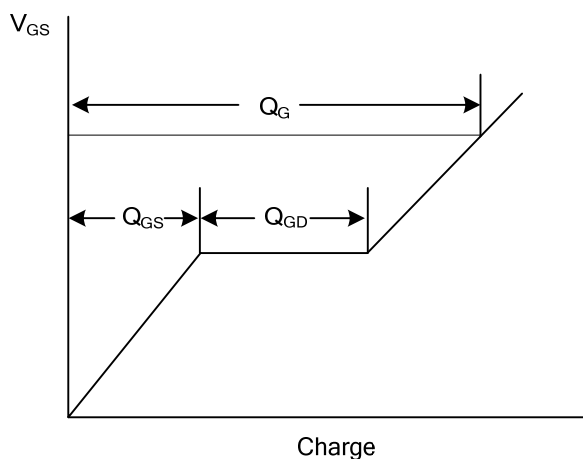
Switching Test Circuit



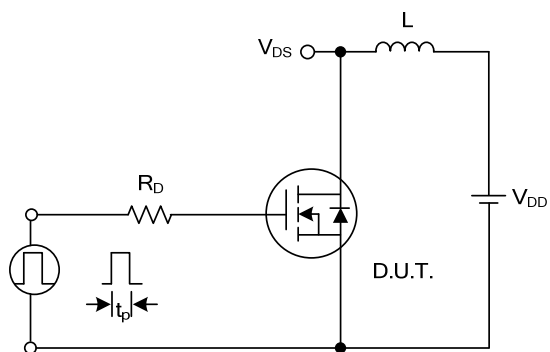
Switching Waveforms



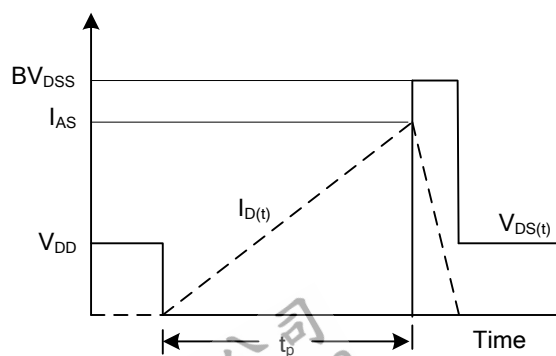
Gate Charge Test Circuit



Gate Charge Waveform

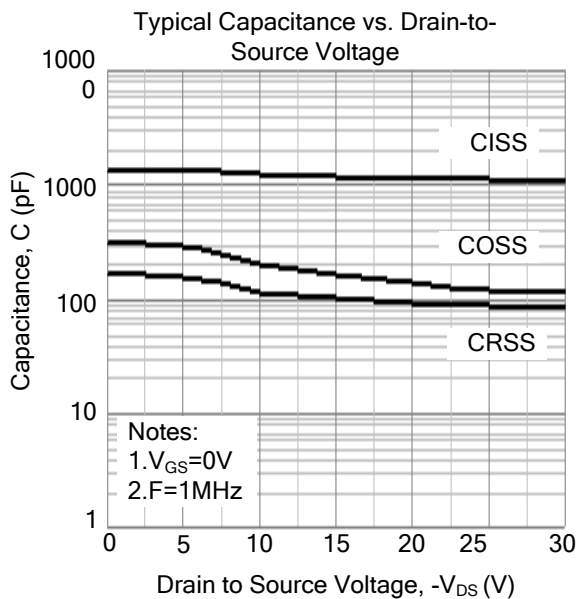
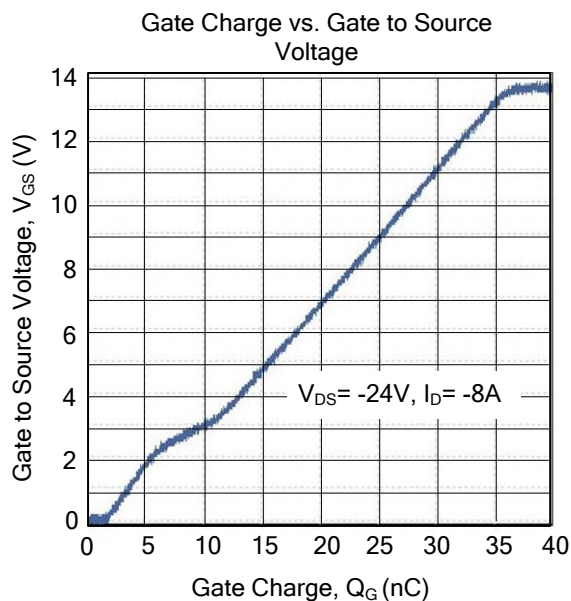


Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

TYPICAL CHARACTERISTICS



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